

The Electrochemical Society

# Solid-State Joint Posters (General)

at the 209<sup>th</sup> ECS Meeting

ECS Transactions Volume 2 No.10

May 7-12, 2006  
Denver, Colorado, USA

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Curran Associates, Inc.  
57 Morehouse Lane  
Red Hook, NY 12571  
[www.proceedings.com](http://www.proceedings.com)

ISBN: 978-1-56677-521-2

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